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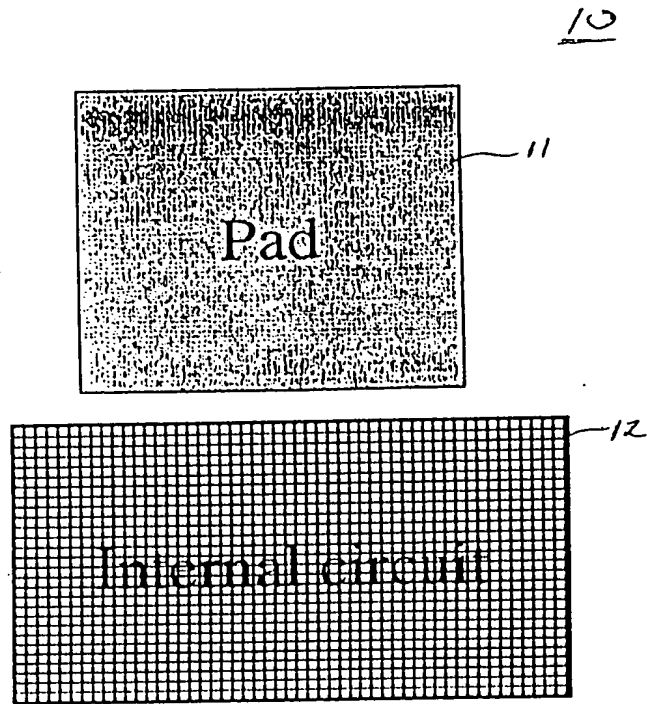
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Top side view

(CONVENTIONAL ART)

Fig. 1

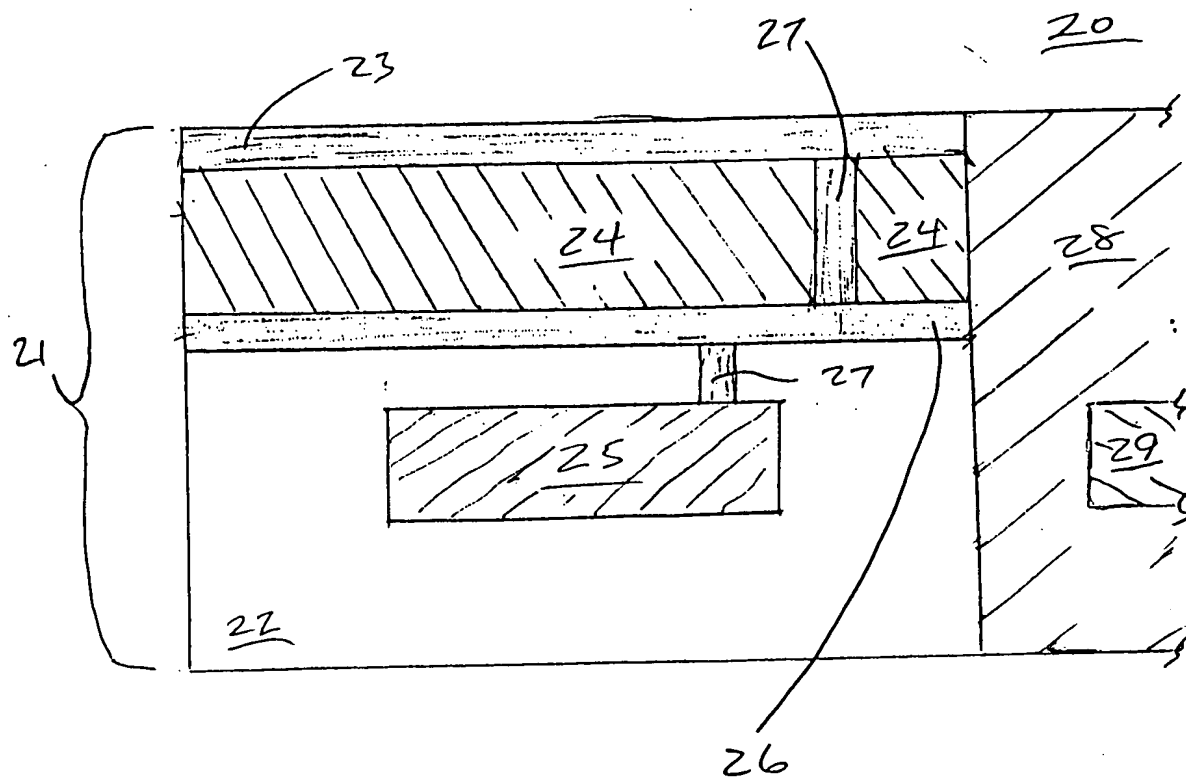
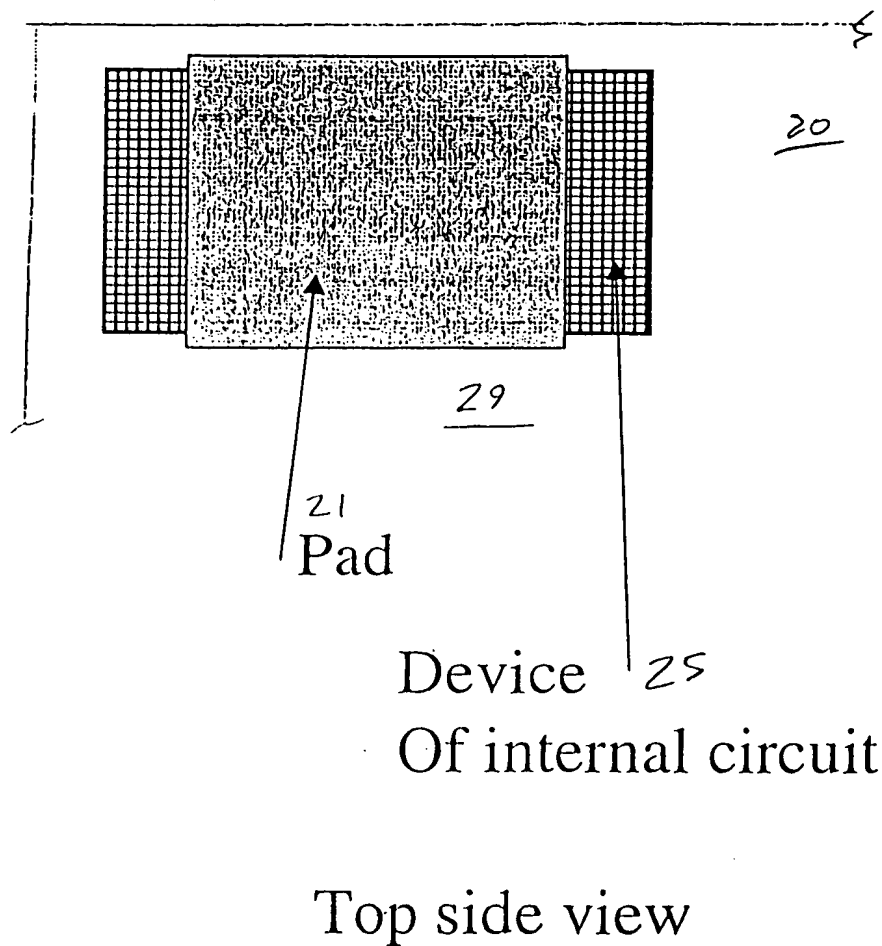
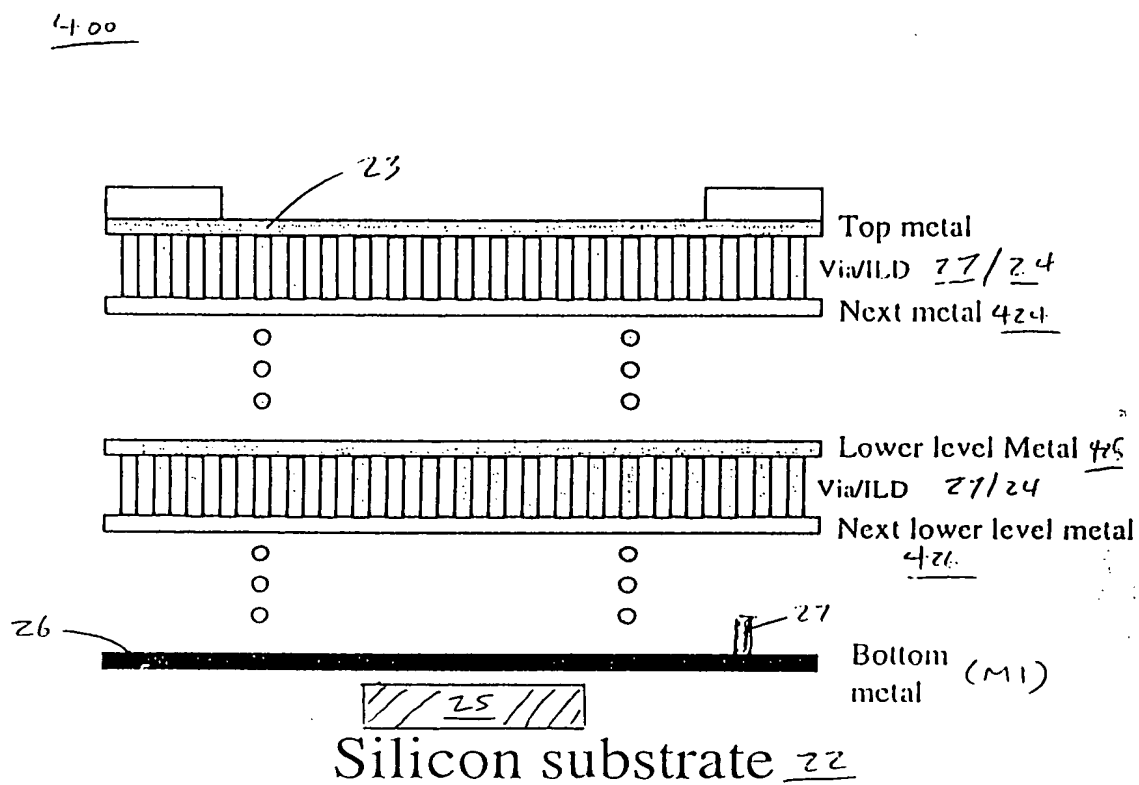


Fig. 2



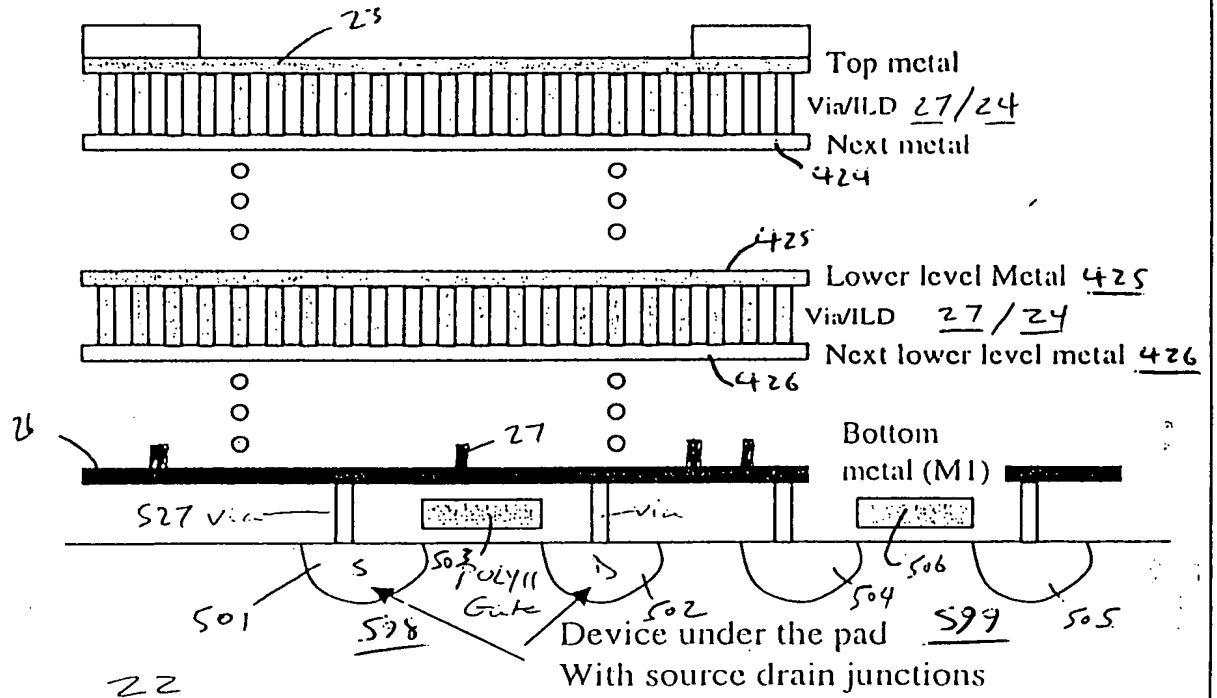
Top side view

Fig. 3



Cross section view

Fig. 4



Cross section view

Fig. 5

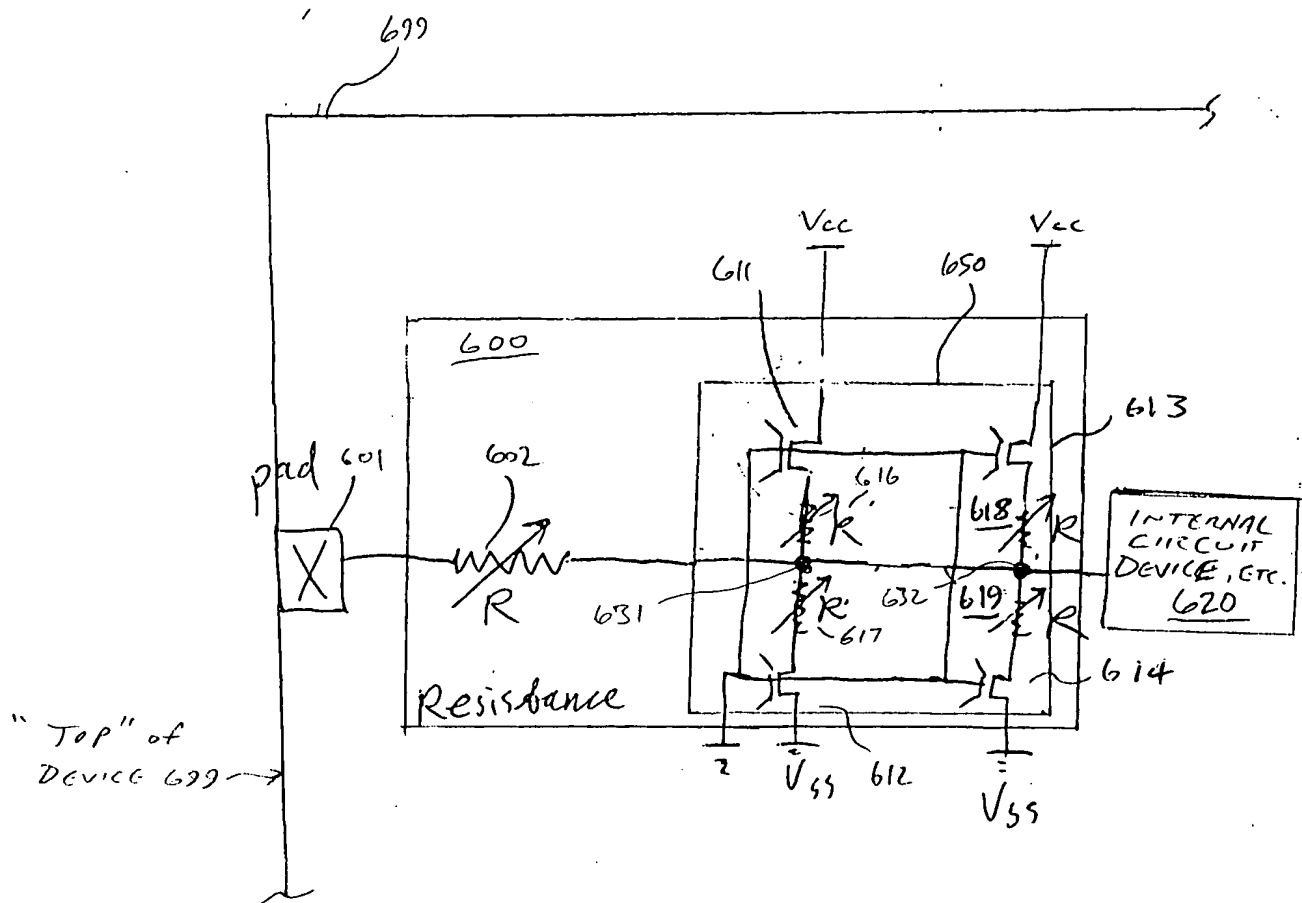


Fig. 6



Fig. 7

80 **Fabricating a Semiconductor Structure with ESD Protection**

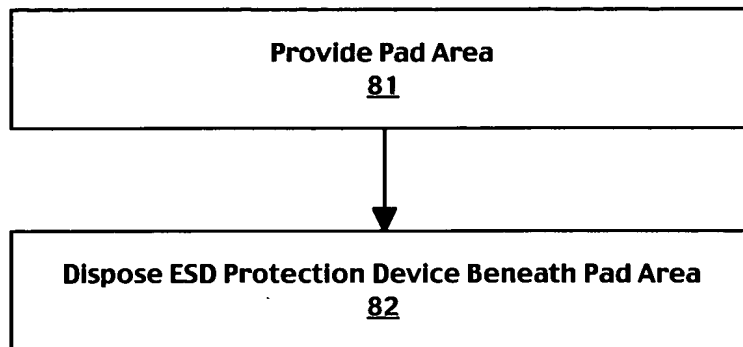


Fig. 8

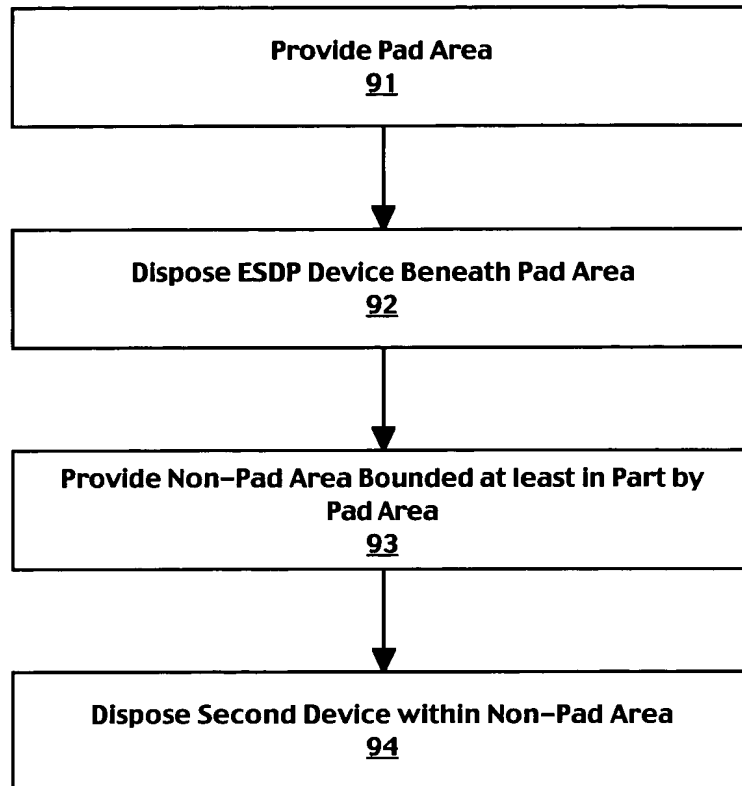


Fig. 9

100

Fabricating a Pad Area

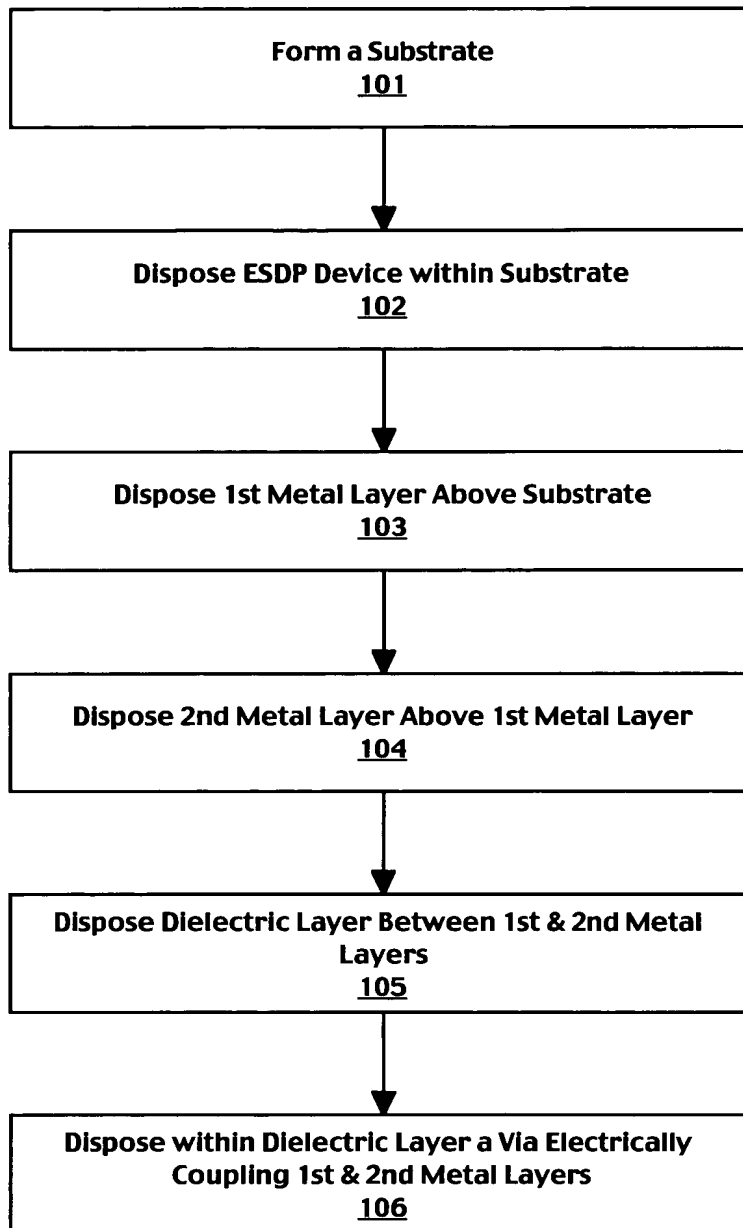


Fig. 10

1100 **Fabricating a Pad Area with ESD Protective Device Below**

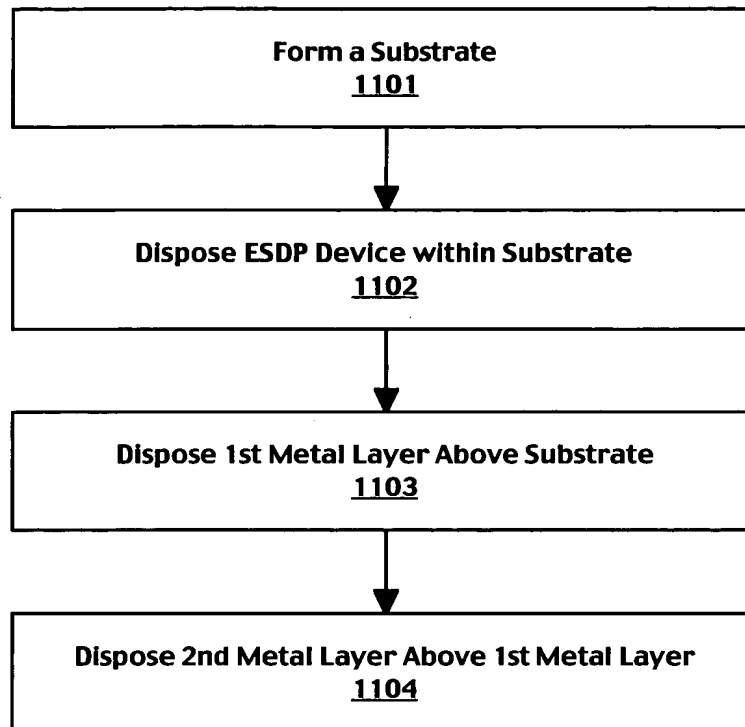


Fig. 11

1200

Fabricating a Pad Area with ESDP Below

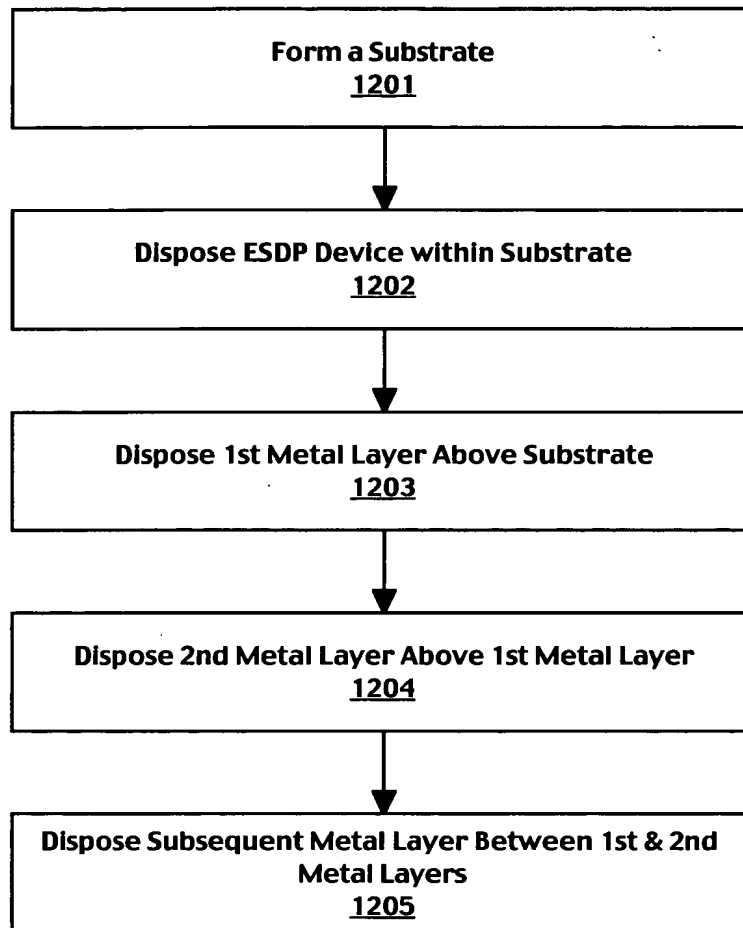


Fig. 12

1300

Fabricating an ESDP Device

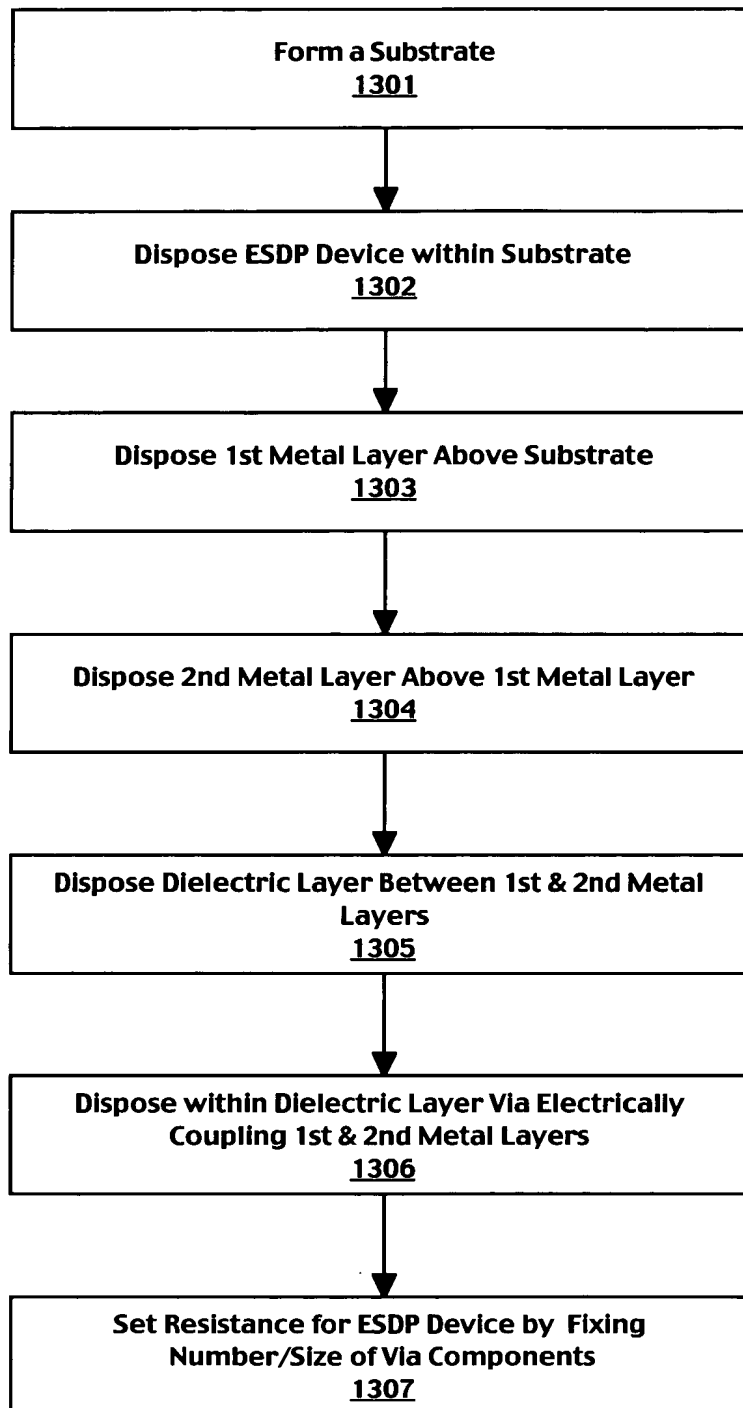


Fig. 13